

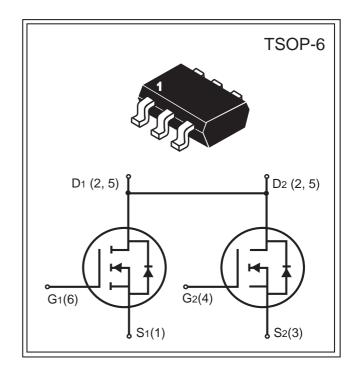
## **Dual N-Channel Enhancement Mode MOSFET**

Product Summary				
VDS (V)	ID (A)	RDS(ON) (m $\Omega$ ) Max		
201/	4.0	30 @VGS = 4.5V		
20V	4A	45 @VGS = 2.5V		

### **FEATURES**

Super high dense cell design for low RDS(ON). Rugged and reliable.

Surface Mount package.



ABSOLUTE MAXIMUM RATINGS (TA = 25°C unless otherwise noted)						
Parameter	Symbol	Limit	Unit			
Drain-Source Voltage	VDS	20	V			
Gate-Source Voltage	Vgs	±10	V			
Drain Current-Continuous @ T <sub>J</sub> = 25°C	lo	4	Α			
-Pulsed <sup>b</sup>	МОІ	25	А			
Drain-Source Diode Forward Current a	Is	2	Α			
Maximum Power Dissipation <sup>a</sup>	Po	1.25	W			
Operating Junction and Storage Temperature Range	Тл, Тѕтс	-55 to 150	°C			
THERMAL CHARACTERISTICS						
Thermal Resistance, Junction-to-Ambient <sup>a</sup>	R JA	100	°C/W			



Electrical Characteristics (T <sub>A</sub> = 25 <sup>o</sup> C unless otherwise noted)						
Parameter	Symbol	Condition	Min	Typ <sup>c</sup>	Max	Unit
Drain-Source Breakdown Voltage	BVpss	Vgs=0V, ID=250 μ A	20			V
Zero Gate Voltage Drain Current	IDSS	VDS=16V, VGS=0V			1	μΑ
Gate-Body Leakage	Igss	Vgs=±8V, Vps=0V			± 100	nA
Gate Threshold Voltage	VGS(th)	Vps=Vgs Ip=250 μ A	0.6	0.8	1.5	V
Drain-Source On-State Resistance	RDS(ON)	Vgs=4.5V, ID=4A		28	30	m
		Vgs=2.5V, ID=3A		35	45	
Forward Transconductance	grs	Vps=5V, Ip=4A		12		S
Input Capacitance	Ciss	VDS=8V		802		
Output Capacitance	Coss	Vgs=0V		153		РF
Reverse Transfer Capacitance	Crss	f=1.0MHz		122		
Turn-On Delay Time	td(ON)	VD=10V,		18		
Rise Time	tr	ID=1A, Vgen=4.5V,		5		
Turn-Off Delay Time	tD(OFF)	RGEN=10 ,		43.8		ns
Fall Time	tf	RL=10		20		
Total Gate Charge	Qg	VDS=10V,		10.5		
Gate-Source Charge	Qgs	ID=4A,		2		nC
Gate-Drain Charge	Qgd	Vgs=4.5V		2.5		
Diode Forward Voltage	Vsp	Vgs=0V, ID=2A		0.82	1.2	V

#### Notes:

- a. Surface Mounted on FR4 Board, t  $\leq$ 10 sec.
- b. Pulse Test : Pulse Width  $\leq 300~\mu\,\text{s},$  Duty Cycle  $\leq 2\%.$
- c. Guaranteed by design, not subject to production testing.



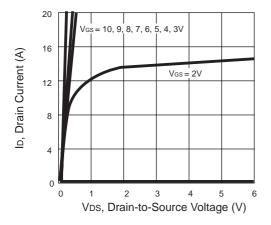


Figure 1. Output Characteristics

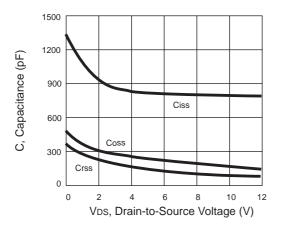


Figure 3. Capacitance

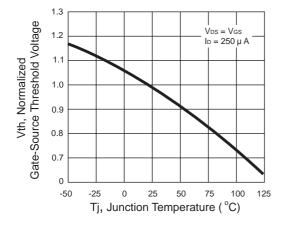


Figure 5. Gate Threshold Variation with Temperature

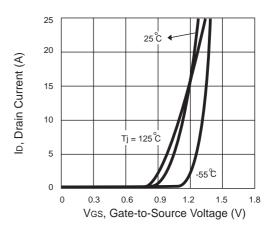


Figure 2. Thansfer Characteristics

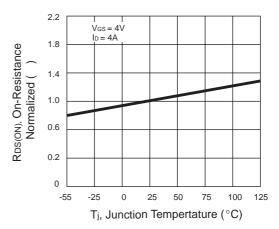


Figure 4. On-Resistance Variation with Temperature

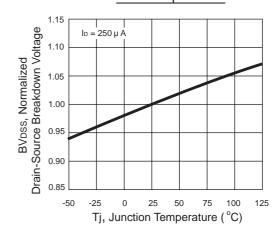


Figure 6. Breakdown Voltage Variation with Temperature





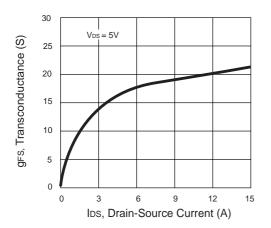


Figure 7. Transconductance Variation with Drain Current

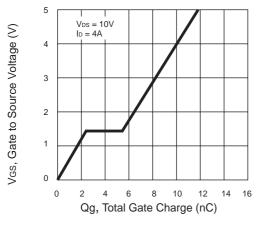


Figure 9. Gate Charge

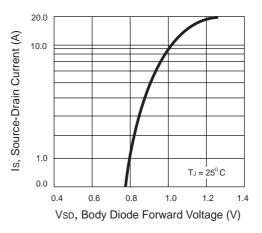


Figure 8. Body Diode Forward Voltage
Variation with Source Current

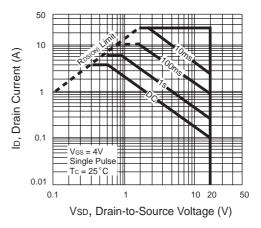
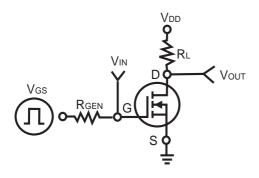


Figure 10. Maximum Safe
Operating Area





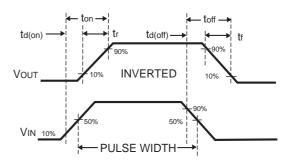


Figure 11. Switching Test Circuit

Figure 12. Switching Waveforms

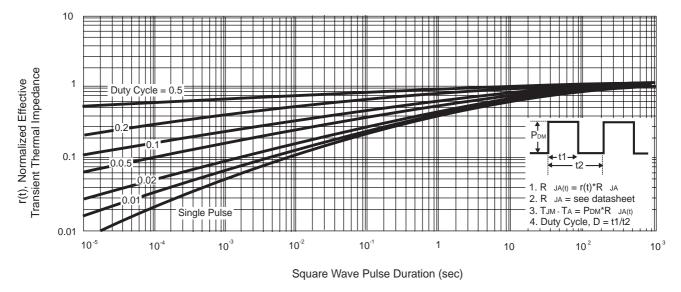
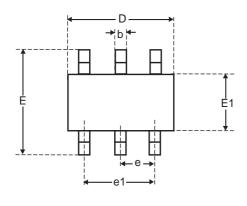


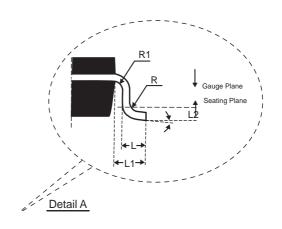
Figure 13. Normalized Thermal Transient Impedance Curve

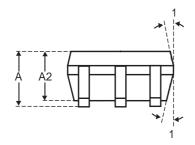


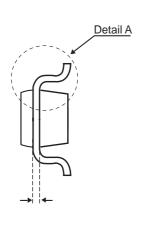
# Package Outline Dimensions

## TSOP-6









SYMBOLS	MILLIMETERS			
	Min.	Nom.	Max.	
А	-	-	1.45	
A2	0.90	0.15	1.30	
b	0.30	-	0.50	
С	0.08	-	0.22	
D	2.70	2.90	3.10	
Е	2.50	2.80	3.10	
E1	1.50	1.60	1.70	
е	0.95 BSC			
e1	1.90 BSC			
L	0.30	0.45 0.60		
L1	0.60 BSC			
L2	0.20 BSC			
R	0.10	-	-	
R1	0.10	-	0.25	
	0 °	4 °	8°	
1	0 °	10°	15°	



